

Measurement methods of a half-wavelength voltage and a chirp parameter for Mach-Zehnder optical modulators in high-frequency radio on fibre (RoF) Systems

EESTI STANDARDI EESSÕNA

NATIONAL FOREWORD

See Eesti standard EVS-EN 62802:2017 sisaldab Euroopa standardi EN 62802:2017 ingliskeelset teksti.	This Estonian standard EVS-EN 62802:2017 consists of the English text of the European standard EN 62802:2017.
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English Version

Measurement methods of a half-wavelength voltage and a chirp
parameter for Mach-Zehnder optical modulators in high-
frequency radio on fibre (RoF) Systems
(IEC 62802:2017)

Méthodes de mesure d'une tension d'une demi-longueur
d'onde et d'un paramètre de fluctuation de la longueur
d'onde pour les modulateurs optiques du type Mach-
Zehnder dans des systèmes radioélectriques sur fibre (RoF,
Radio on Fibre), à haute fréquence
(IEC 62802:2017)

Messverfahren von Halbwellenlängenspannungen und
Chirp-Parameter für Optische Mach-Zehnder Modulatoren
in HF-Rundfunk-über-Glasfaser-Übertragungssystemen
(RoF)
(IEC 62802:2017)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

European foreword

The text of document 103/131/CDV, future edition 1 of IEC 62802, prepared by IEC/TC 103 "Transmitting equipment for radiocommunication" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62802:2017.

The following dates are fixed:

- latest date by which the document has to be (dop) 2018-06-01
implemented at national level by
publication of an identical national
standard or by endorsement
- latest date by which the national (dow) 2020-12-01
standards conflicting with the
document have to be withdrawn

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Endorsement notice

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In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 61280-2-9	NOTE	Harmonized as EN 61280-2-9.
IEC 61280-10	NOTE	Harmonized as EN 61280-10.

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 62007-1	-	Semiconductor optoelectronic devices for fibre optic system applications - Part 1: Specification template for essential ratings and characteristics	EN 62007-1	-
IEC 62007-2	-	Semiconductor optoelectronic devices for fibre optic system applications - Part 2: Measuring methods	EN 62007-2	-

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INTRODUCTION

A variety of microwave/millimeter-wave-photonic devices are useful for wireless communication and broadcasting systems. An optical modulator is an interface which converts an electronic signal to an optical signal. In the field of optical fibre communication systems, the IEC 62007 series was published in 1999.

Microwave/millimeter-wave RoF systems are comprised mainly of two parts: one is RF to photonic converter (E/O), and the other is photonic to RF converter (O/E). Radio waves are converted into an optical signal at E/O. This signal is transferred through the optical fibre and then the radio waves are regenerated at O/E.

A variety of photonic devices that carry microwave and millimeter-wave signals as subcarrier frequencies are used for high-frequency RoF systems. In particular, the Mach-Zehnder optical modulator (MZM) plays an important role to convert electronic (high-frequency above millimeter-wave) signal to optical signal. In high-frequency RoF systems, specifications of drive voltages, chirp characteristics, inter-modulation distortion of the modulators have been the important technical parameters. This document is prepared to provide the measurement method of MZMs to the industry for evaluating electro-optic material of the modulators to be used in high-frequency RoF systems. This document defines the measurement methods of a half-wavelength voltage and a chirp parameter, which have a significant impact on the performance of RoF systems. Additionally, these methods are also used for the estimation of the intermodulation distortions and transmission performances.

The half-wavelength voltage and the chirp parameter can be measured at the same time using the methods defined in this document. The nonlinear distortion characteristics are also important for the performance of the systems. The intermodulation distortion of the MZM is calculated from the driving voltage and the half-wavelength voltage. The detailed explanations and calculation method of intermodulation distortions from the normalized optical modulation index (NOMI) are described in IEC PAS 62593:2008[1]¹, Annex B.

The International Electrotechnical Commission (IEC) draws attention to the fact that it is claimed that compliance with this document may involve the use of patents concerning:

- a) a method for characterization of optical modulator, and method for controlling high frequency oscillator using the same (JP 3538619B),
- b) a method and apparatus for measurement of characteristic of optical modulator (JP 3866082B),
- c) a method for evaluating characteristic of optical modulator having Mach-Zehnder interferometer (WO 2011-027409),
- d) a method of measuring half-wave voltage of optical modulator (JP 2009-229926A).

Details pertaining to the patent holders and the locations where the patents are referred to in the document are given in Table 1.

¹ Numbers in square brackets refer to the Bibliography.

Table 1 – Patents present in this document

Related clause	Patent holder	Patent number
Clause 6 Annex A (informative)	National Institute of Information and Communications Technology	JP 3538619
6.4.3	National Institute of Information and Communications Technology Sumitomo Osaka Cement Co., Ltd.	JP 3866082
A.2.1	National Institute of Information and Communications Technology Sumitomo Osaka Cement Co., Ltd.	(WO 2011-027409) EP 2477021A US 8867042 CN 102575971 JP 5622154
A.2.2	Sumitomo Osaka Cement Co., Ltd.	(JP2009-229926A) JP 4991610

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